

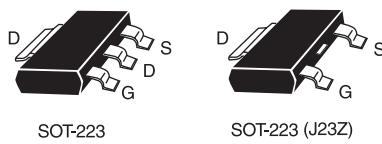
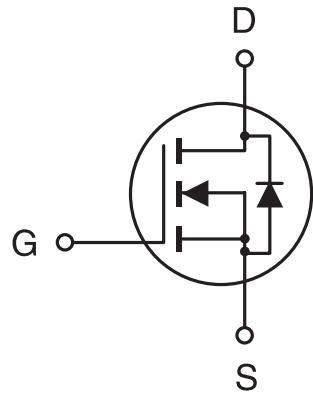
# CET453N

March 1998

## N-Channel Enhancement Mode Field Effect Transistor

### FEATURES

- 30V , 8A ,  $R_{DS(ON)}=28m\Omega$  @  $V_{GS}=10V$ .  
 $R_{DS(ON)}=42m\Omega$  @  $V_{GS}=4.5V$ .
- High dense cell design for low  $R_{DS(ON)}$ .
- Rugged and reliable.
- SOT-223 Package.



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### ABSOLUTE MAXIMUM RATINGS (TA=25°C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	30	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Drain Current-Continuous <sup>a</sup> @ T <sub>J</sub> =125°C -Pulsed <sup>b</sup>	I <sub>D</sub>	±8	A
	I <sub>DM</sub>	±15	A
Drain-Source Diode Forward Current <sup>a</sup>	I <sub>S</sub>	2.3	A
Maximum Power Dissipation <sup>a</sup>	P <sub>D</sub>	3	W
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-65 to 150	°C

### THERMAL CHARACTERISTICS

Thermal Resistance, Junction-to-Ambient <sup>a</sup>	R <sub>θJA</sub>	42	°C/W
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## ELECTRICAL CHARACTERISTICS (TA=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	30			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =24V, V <sub>GS</sub> =0V			1	μA
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V			±100	nA
<b>ON CHARACTERISTICS<sup>b</sup></b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> = 250μA	1	1.6	3	V
Drain-Source On-State Resistance	R <sub>DSON</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =8A		22	28	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =6.7A		33	42	mΩ
On-State Drain Current	I <sub>D(ON)</sub>	V <sub>DS</sub> =5V, V <sub>GS</sub> =10V	15			A
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =15V, I <sub>D</sub> =8A	6	14		S
<b>DYNAMIC CHARACTERISTICS<sup>c</sup></b>						
Input Capacitance	C <sub>ISS</sub>	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 0V f = 1.0MHz		707	920	pF
Output Capacitance	C <sub>OSS</sub>			355	460	pF
Reverse Transfer Capacitance	C <sub>RSS</sub>			89	120	pF
<b>SWITCHING CHARACTERISTICS<sup>c</sup></b>						
Turn-On Delay Time	t <sub>D(ON)</sub>	V <sub>DD</sub> = 25V, I <sub>D</sub> = 1A, V <sub>GEN</sub> = 10V, R <sub>GEN</sub> = 6Ω		10	15	ns
Rise Time	t <sub>r</sub>			20	35	ns
Turn-Off Delay Time	t <sub>D(OFF)</sub>			40	50	ns
Fall time	t <sub>f</sub>			35	50	ns
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> = 15V, I <sub>D</sub> = 8A, V <sub>GS</sub> = 10V		22	35	nC
Gate-Source Charge	Q <sub>gs</sub>			4		nC
Gate-Drain Charge	Q <sub>gd</sub>			3		nC

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## ELECTRICAL CHARACTERISTICS ( $T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>DRAIN-SOURCE DIODE CHARACTERISTICS<sup>b</sup></b>						
Diode Forward Voltage	$V_{SD}$	$V_{GS} = 0V, I_S = 8A$		0.8	1.3	V

### Notes

- a. Surface Mounted on FR4 Board,  $t \leq 10\text{ sec}$ .
- b. Pulse Test: Pulse Width  $\leq 300 \mu\text{s}$ , Duty Cycle  $\leq 2\%$ .
- c. Guaranteed by design, not subject to production testing.

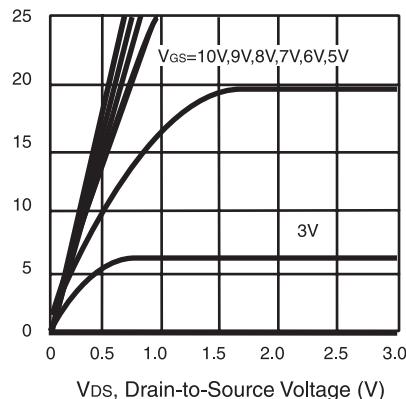


Figure 1. Output Characteristics

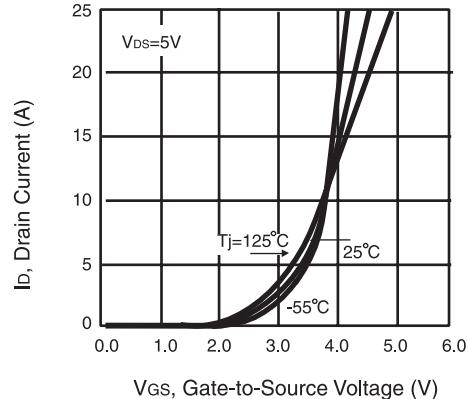


Figure 2. Transfer Characteristics

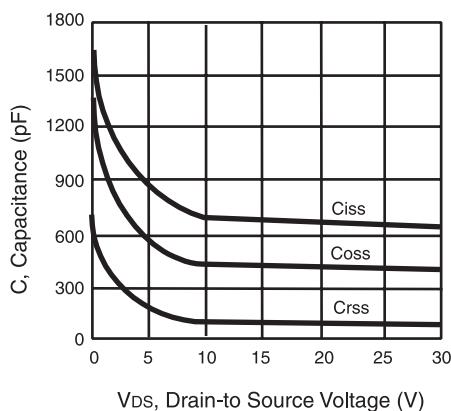


Figure 3. Capacitance

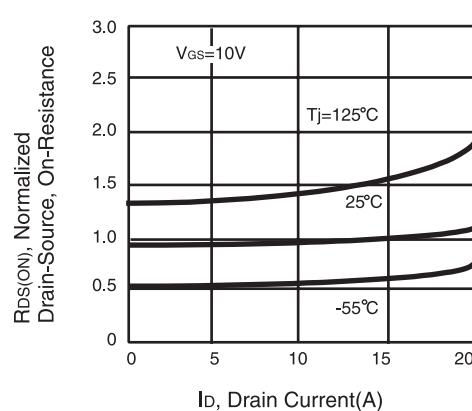


Figure 4. On-Resistance Variation with Drain Current and Temperature

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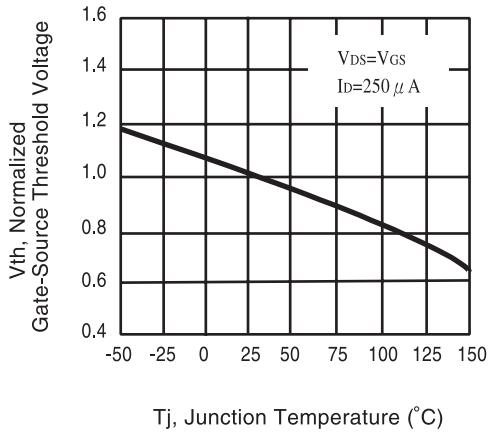


Figure 5. Gate Threshold Variation with Temperature

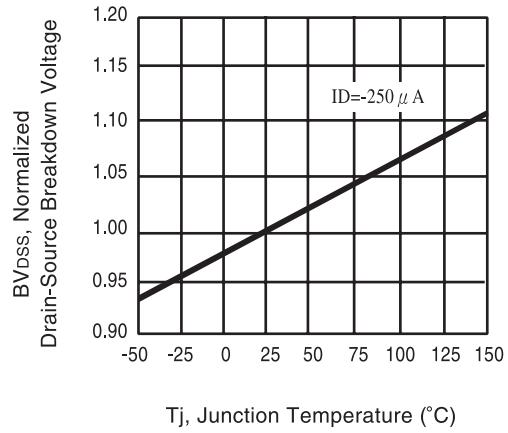


Figure 6. Breakdown Voltage Variation with Temperature

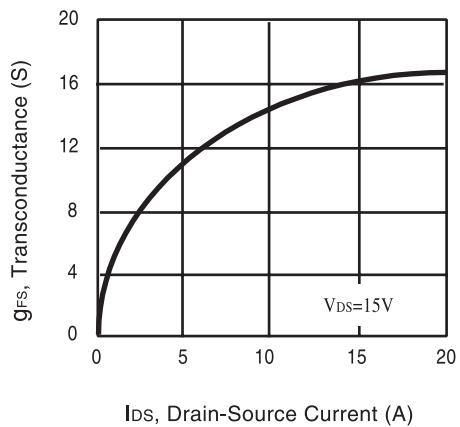


Figure 7. Transconductance Variation with Drain Current

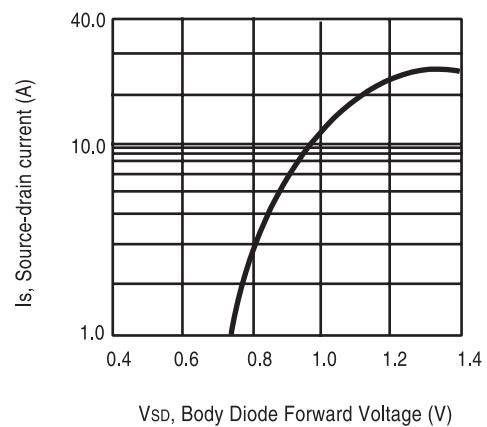


Figure 8. Body Diode Forward Voltage Variation with Source Current

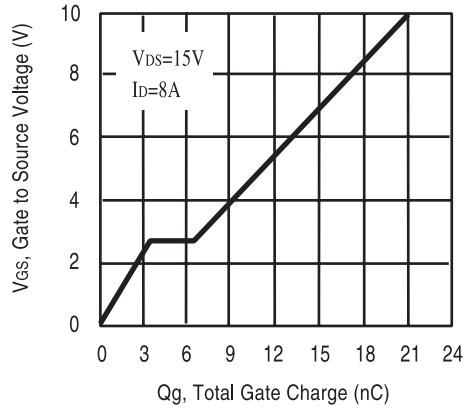


Figure 9. Gate Charge

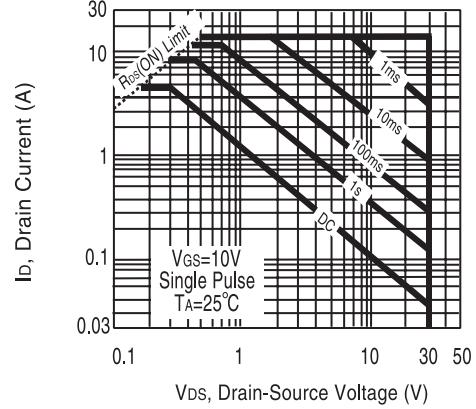


Figure 10. Maximum Safe Operating Area

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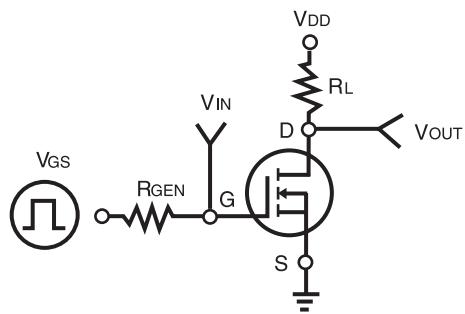


Figure 11. Switching Test Circuit

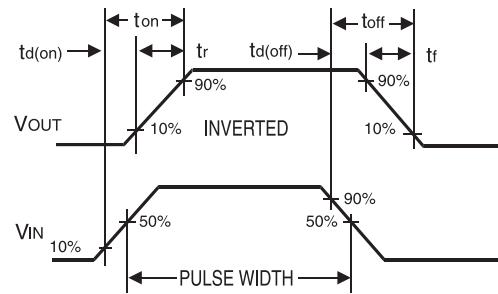


Figure 12. Switching Waveforms

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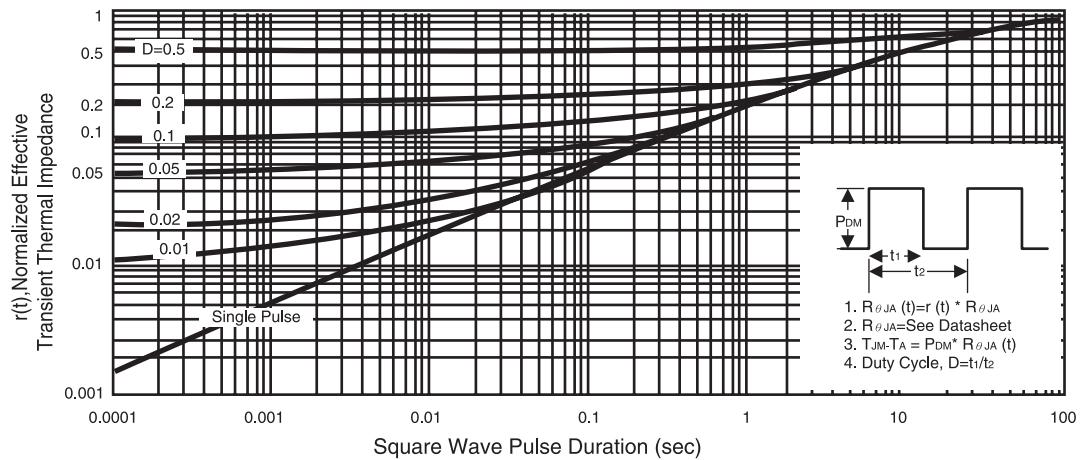


Figure 13. Normalized Thermal Transient Impedance Curve